

Search Notes

Application No.

10/698,198

Examiner

Patrick Miller

Applicant(s)

POON ET AL.

Art Unit

2837

SEARCHED

| Class | Subclass | Date | Examiner |
|-------|---|-----------|----------|
| 318 | 568.17,59 2,593,649, 623,625,3 8 | 9/30/2004 | PM |
| 318 | 40,135 | 9/30/2004 | PM |
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INTERFERENCE SEARCHED

| Class | Subclass | Date | Examiner |
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**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

| | DATE | EXMR |
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| fine and coarse; counter weight/balance/mass; vacuum; magnet track; lithography; EUVL; x-y stage | 9/30/2004 | PM |
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